

1. Record Nr.	UNINA9910254230103321
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Titolo	CMOS RF Circuit Design for Reliability and Variability // by Jiann-Shiun Yuan
Pubbl/distr/stampa	Singapore : , : Springer Singapore : , : Imprint : Springer, , 2016
ISBN	981-10-0884-1
Edizione	[1st ed. 2016.]
Descrizione fisica	1 online resource (108 p.)
Collana	SpringerBriefs in Reliability, , 2196-1123
Disciplina	621.38412
Soggetti	Electronic circuits Microwaves Optical engineering Circuits and Systems Electronic Circuits and Devices Microwaves, RF and Optical Engineering
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references at the end of each chapters.
Nota di contenuto	CMOS Transistor Reliability and Variability -- Wireless Receiver and Transmitter Circuit Reliability -- Low Noise Amplifier Reliability and Variability -- Power Amplifier Reliability and Variability -- Voltage Controlled Oscillator Reliability and Variability -- Mixer Reliability.
Sommario/riassunto	The subject of this book is CMOS RF circuit design for reliability. The device reliability and process variation issues on RF transmitter and receiver circuits will be particular interest to the readers in the field of semiconductor devices and circuits. This proposed book is unique to explore typical reliability issues in the device and technology level and then to examine their impact on RF wireless transceiver circuit performance. Analytical equations, experimental data, device and circuit simulation results will be given for clear explanation. The main benefit the reader derive from this book will be clear understanding on how device reliability issues affects the RF circuit performance subjected to operation aging and process variations.